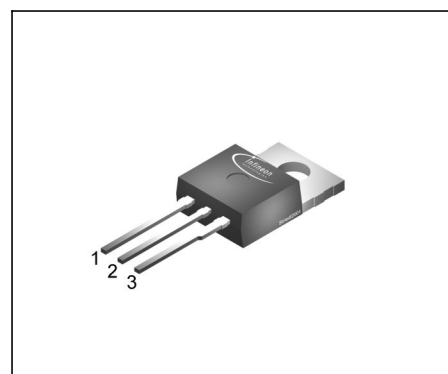


**SIPMOS<sup>®</sup> Power Transistor**

- N channel
- Enhancement mode
- Avalanche-rated
- Pb-free lead plating; RoHS compliant



Pin 1	Pin 2	Pin 3
G	D	S

Type	V <sub>DS</sub>	I <sub>D</sub>	R <sub>DS(on)</sub>	Package	Pb-free
BUZ 30A	200 V	21 A	0.13 Ω	PG-TO-220-3	Yes

**Maximum Ratings**

Parameter	Symbol	Values	Unit
Continuous drain current <i>T<sub>C</sub></i> = 26 °C	I <sub>D</sub>	21	A
Pulsed drain current <i>T<sub>C</sub></i> = 25 °C	I <sub>Dpuls</sub>	84	
Avalanche current, limited by <i>T<sub>jmax</sub></i>	I <sub>AR</sub>	21	
Avalanche energy, periodic limited by <i>T<sub>jmax</sub></i>	E <sub>AR</sub>	12	mJ
Avalanche energy, single pulse I <sub>D</sub> = 21 A, V <sub>DD</sub> = 50 V, R <sub>GS</sub> = 25 Ω L = 1.53 mH, <i>T<sub>j</sub></i> = 25 °C	E <sub>AS</sub>	450	
Gate source voltage	V <sub>GS</sub>	± 20	V
Power dissipation <i>T<sub>C</sub></i> = 25 °C	P <sub>tot</sub>	125	W
Operating temperature	<i>T<sub>j</sub></i>	-55 ... + 150	°C
Storage temperature	<i>T<sub>stg</sub></i>	-55 ... + 150	
Thermal resistance, chip case	R <sub>thJC</sub>	≤ 1	K/W
Thermal resistance, chip to ambient	R <sub>thJA</sub>	75	
DIN humidity category, DIN 40 040		E	
IEC climatic category, DIN IEC 68-1		55 / 150 / 56	

**Electrical Characteristics**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
<b>Static Characteristics</b>					
Drain- source breakdown voltage $V_{GS} = 0\text{ V}$ , $I_D = 0.25\text{ mA}$ , $T_j = 25^\circ\text{C}$	$V_{(BR)DSS}$	200	-	-	V
Gate threshold voltage $V_{GS} = V_{DS}$ , $I_D = 1\text{ mA}$	$V_{GS(th)}$	2.1	3	4	
Zero gate voltage drain current $V_{DS} = 200\text{ V}$ , $V_{GS} = 0\text{ V}$ , $T_j = 25^\circ\text{C}$ $V_{DS} = 200\text{ V}$ , $V_{GS} = 0\text{ V}$ , $T_j = 125^\circ\text{C}$	$I_{DSS}$	-	0.1 10	1 100	$\mu\text{A}$
Gate-source leakage current $V_{GS} = 20\text{ V}$ , $V_{DS} = 0\text{ V}$	$I_{GSS}$	-	10	100	nA
Drain-Source on-resistance $V_{GS} = 10\text{ V}$ , $I_D = 13.5\text{ A}$	$R_{DS(on)}$	-	0.1	0.13	$\Omega$

**Electrical Characteristics**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

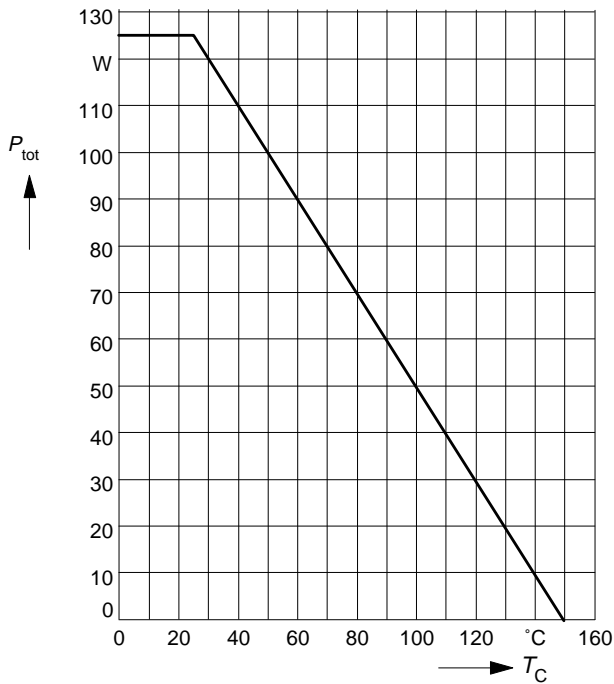
Parameter	Symbol	Values			Unit
		min.	typ.	max.	
<b>Dynamic Characteristics</b>					
Transconductance $V_{DS} \geq 2 * I_D * R_{DS(on)max}$ , $I_D = 13.5\text{ A}$	$g_{fs}$	6	15	-	S
Input capacitance $V_{GS} = 0\text{ V}$ , $V_{DS} = 25\text{ V}$ , $f = 1\text{ MHz}$	$C_{iss}$	-	1400	1900	pF
Output capacitance $V_{GS} = 0\text{ V}$ , $V_{DS} = 25\text{ V}$ , $f = 1\text{ MHz}$	$C_{oss}$	-	280	400	
Reverse transfer capacitance $V_{GS} = 0\text{ V}$ , $V_{DS} = 25\text{ V}$ , $f = 1\text{ MHz}$	$C_{rss}$	-	130	200	
Turn-on delay time $V_{DD} = 30\text{ V}$ , $V_{GS} = 10\text{ V}$ , $I_D = 3\text{ A}$ $R_{GS} = 50\ \Omega$	$t_{d(on)}$	-	30	45	ns
Rise time $V_{DD} = 30\text{ V}$ , $V_{GS} = 10\text{ V}$ , $I_D = 3\text{ A}$ $R_{GS} = 50\ \Omega$	$t_r$	-	70	110	
Turn-off delay time $V_{DD} = 30\text{ V}$ , $V_{GS} = 10\text{ V}$ , $I_D = 3\text{ A}$ $R_{GS} = 50\ \Omega$	$t_{d(off)}$	-	250	320	
Fall time $V_{DD} = 30\text{ V}$ , $V_{GS} = 10\text{ V}$ , $I_D = 3\text{ A}$ $R_{GS} = 50\ \Omega$	$t_f$	-	90	120	

**Electrical Characteristics**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
<b>Reverse Diode</b>					
Inverse diode continuous forward current $T_C = 25^\circ\text{C}$	$I_S$	-	-	21	A
Inverse diode direct current, pulsed $T_C = 25^\circ\text{C}$	$I_{SM}$	-	-	84	A
Inverse diode forward voltage $V_{GS} = 0\text{ V}, I_F = 42\text{ A}$	$V_{SD}$	-	1.2	1.6	V
Reverse recovery time $V_R = 100\text{ V}, I_F = I_S, di_F/dt = 100\text{ A}/\mu\text{s}$	$t_{rr}$	-	180	-	ns
Reverse recovery charge $V_R = 100\text{ V}, I_F = I_S, di_F/dt = 100\text{ A}/\mu\text{s}$	$Q_{rr}$	-	1.2	-	$\mu\text{C}$

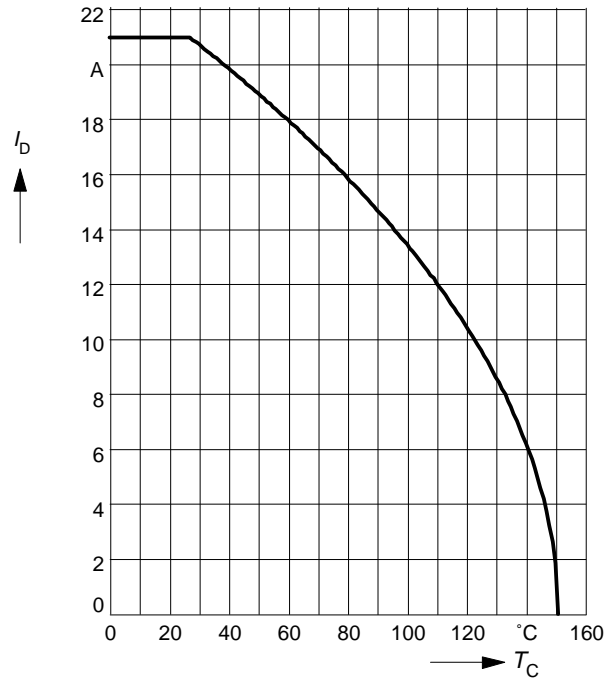
**Power dissipation**

$P_{tot} = f(T_C)$



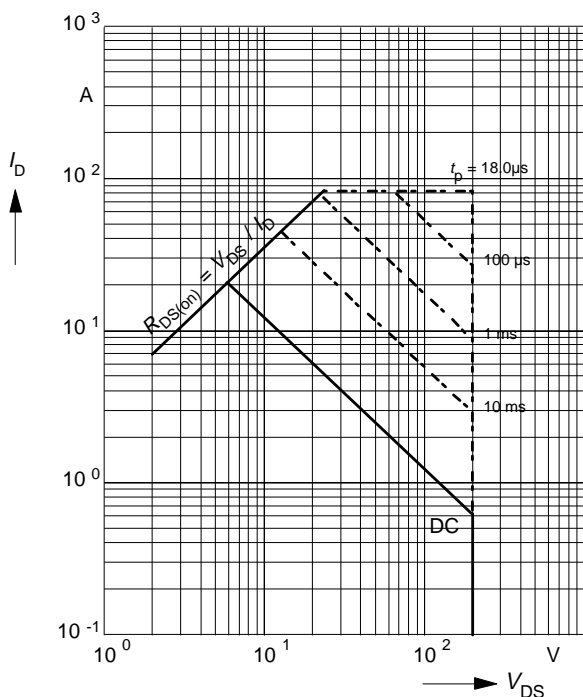
**Drain current**

$I_D = f(T_C)$   
parameter:  $V_{GS} \geq 10\text{ V}$



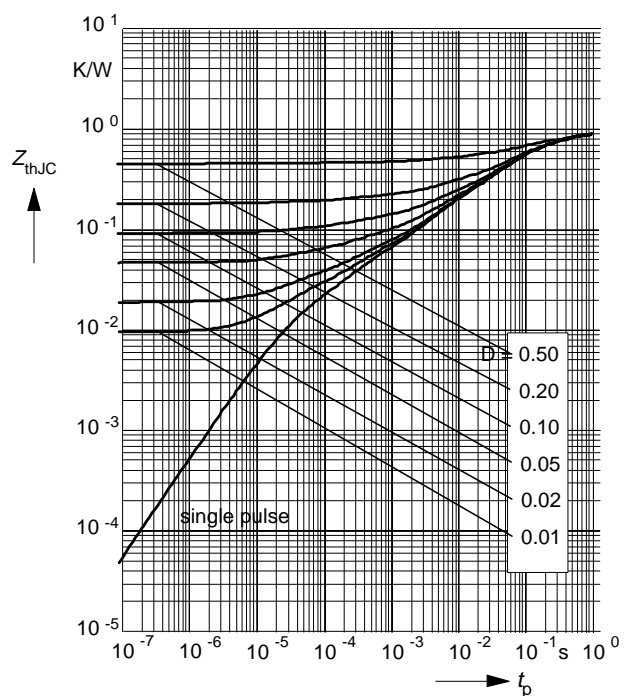
**Safe operating area**

$I_D = f(V_{DS})$   
parameter:  $D = 0.01, T_C = 25^\circ\text{C}$



**Transient thermal impedance**

$Z_{thJC} = f(t_p)$   
parameter:  $D = t_p / T$



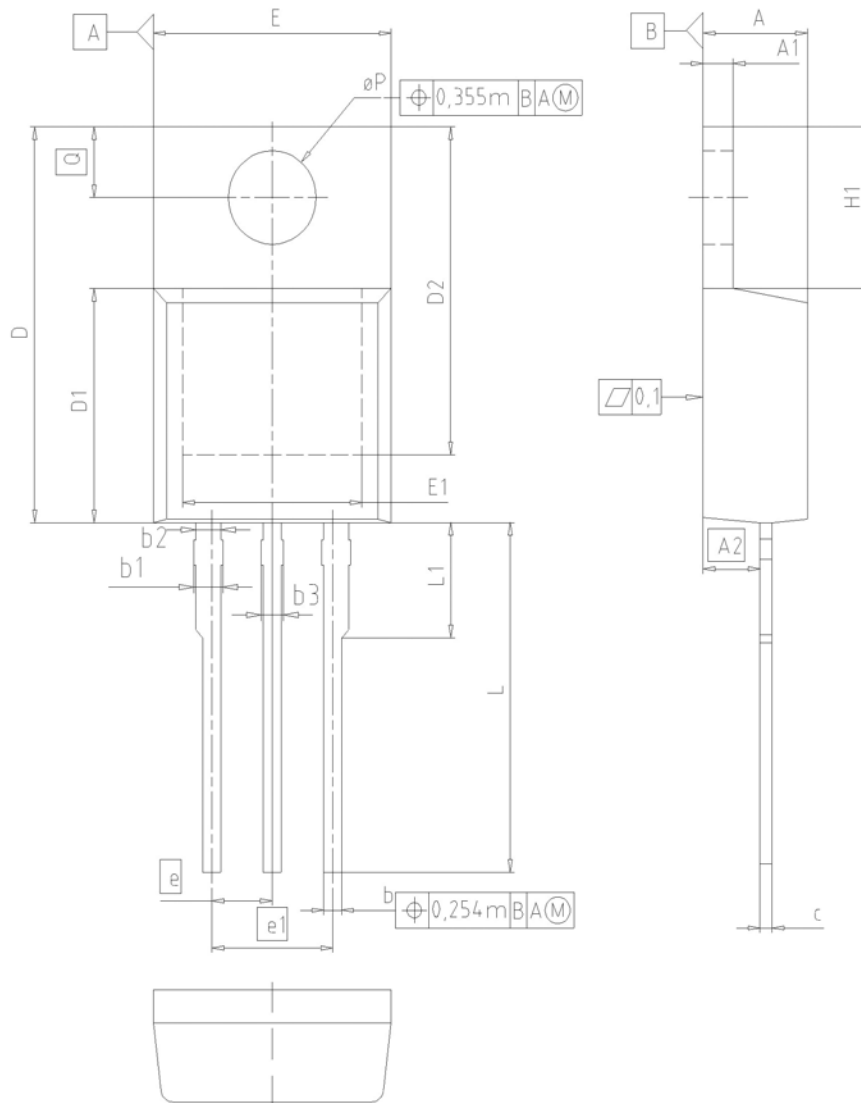








PG-TO220-3



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
b1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
c	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
e	2.54		0.100	
e1	5.08		0.200	
N	3		3	
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
$\phi P$	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118

**DOCUMENT NO.**  
Z8B0003318

**SCALE**

**EUROPEAN PROJECTION**

**ISSUE DATE**  
23-08-2007

**REVISION**  
05

**Published by**  
**Infineon Technologies AG**  
**81726 Munich, Germany**  
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